

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/005,043	YEH ET AL.	
Examiner	Art Unit	
Jungwon Chang	2154	

SEARCHED					
Class	Subclass	Date	Examiner		
700	83	10/15/2007	JWC		
700	19	10/15/2007	JWC		
710	8	10/15/2007	JWC		
710	63	10/15/2007	JWC		
709	250	10/15/2007	JMC		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
700	83	10/15/2007	JWC	
700	19	10/15/2007	JMC	
710	8	10/15/2007	JWC	
710/63 709/250		10/15/2007	JWC	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
East Google ACM Search report attached	10/15/2007	JWC			
Inventor name searched	10/15/2007	JWC			
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